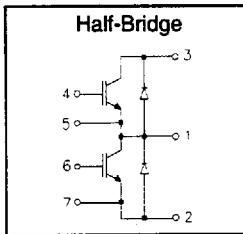
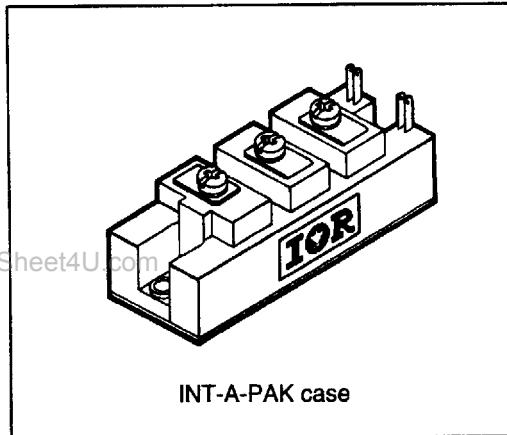


**IRGTIN100M06****"HALF-BRIDGE" IGBT INT-A-PAK****Low conduction loss IGBT**

- Rugged Design
- Simple gate-drive
- Switching-Loss Rating includes all "tail" losses
- Short circuit rated



$V_{CE} = 600V$   
 $I_C = 100A$   
 $V_{CE(ON)} < 2.0V$   
 $t_{sc} > 10\mu s$

**Description**

IR's advanced IGBT technology is the key to this line of INT-A-PAK Power Modules. The efficient geometry and unique processing of the IGBT allow higher current densities than comparable bipolar power module transistors, while at the same time requiring the simpler gate-drive of the familiar power MOSFET. These modules are short circuit rated for applications such as motor control requiring this important feature.

**Absolute Maximum Ratings**

Parameter	Description	Value	Units
$V_{CES}$	Continuous collector to emitter voltage	600	V
$I_C @ T_C = 25^\circ C$	Continuous collector current	150	A
$I_C @ T_C = 85^\circ C$	Continuous collector current	80	
$I_C @ T_C = 100^\circ C$	Continuous collector current	60	
$I_{LM}$	Peak switching current	200	
$I_{FM}$	Peak diode forward current (1)	200	
$V_{GE}$	Gate to emitter voltage	$\pm 20$	V
$V_{ISOL}$	RMS isolation voltage, any terminal to case, $t = 1 \text{ min}$	2500	
$P_D @ T_C = 25^\circ C$	Power dissipation	500	W
$T_J$	Operating junction temperature range	-40 to 150	$^\circ C$
$T_{STG}$	Storage temperature range	-40 to 125	

(1) Duration limited by max junction temperature.

## IRGTIN100M06

## Target Data

Electrical Characteristics -  $T_J = 25^\circ C$ , unless otherwise stated

Parameter	Description	Min	Typ	Max	Units	Test Conditions
$BV_{CES}$	Collector-to-emitter breakdown voltage	600	—	—	V	$V_{GE} = 0V, I_C = 1.5mA$
$V_{CE}(ON)$	Collector-to-emitter voltage	—	—	2.0		$V_{GE} = 15V, I_C = 100A$
		—	2.2	—		$V_{GE} = 15V, I_C = 100A, T_J = 125^\circ C$
$V_{FM}$	Diode forward voltage - maximum	—	1.8	2.0		$I_F = 100A, V_{GE} = 0V$
		—	1.75	—		$I_F = 100A, V_{GE} = 0V, T_J = 125^\circ C$
		—	—	—		$I_C = 750\mu A$
$V_{GEth}$	Gate threshold voltage	3.0	—	5.5		
$\Delta V_{GEth}$	Threshold voltage temp. coefficient	—	-11	—	mV/C	$V_{CE} = V_{GE}, I_C = 750\mu A$
$g_{fe}$	Forward transconductance	78	—	108	S(Ω)	$V_{CE} = 25V, I_C = 100A$
$I_{CES}$	Collector-to-emitter leakage current	—	—	1.5	mA	$V_{GE} = 0V, V_{CE} = 600V$
		—	—	15		$V_{GE} = 0V, V_{CE} = 600V, T_J = 125^\circ C$
$I_{GES}$	Gate-to-emitter leakage current	—	—	$\pm 1.5$	μA	$V_{GE} = \pm 20V$

Dynamic Characteristics -  $T_J = 125^\circ C$ , unless otherwise stated

Parameter	Description	Min	Typ	Max	Units	Test Conditions
$E_{on}$	Turn-on switching energy	—	0.03	—	mJ/A	$R_G = 18\Omega, V_{CC} = 300V$
$E_{off}$ (1)		—	0.11	—		$I_C = 100A, L_S = 100nH$
$E_{ts}$ (1)		—	—	0.18		$V_{GE} = \pm 15V$
$t_{d(on)}$	Turn-on delay time	—	200	—	ns	$R_G = 18\Omega, V_{CC} = 300V$
		—	400	—		$I_C = 100A$
		—	250	—		$V_{GE} = \pm 15V$
		—	350	—		Resistive load, $T_J = 25^\circ C$
$I_{rr}$	Diode peak recovery current	—	40	—	A	$R_G = 18\Omega, V_{CC} = 300V$
		—	110	—		$I_C = 100A$
		—	2.2	—		$V_{GE} = \pm 15V$
$Q_{rr}$	Diode recovery time	39	—	63	nC	$V_{CC} = 480V$
		105	—	210		$I_C = 81A$
		225	—	420		$V_{GE} = 15V$
$Q_{ge}$	Gate-to-emitter charge (turn-on)	—	8700	—	pF	$V_{GE} = 0V$
		—	990	—		$V_{CC} = 30V$
		—	120	—		f = 1MHz
$C_{ies}$	Input capacitance	—	—	—	μs	$V_{CC} = 360V, V_{GE} = \pm 15V$
$C_{oes}$	Output capacitance	—	—	—		Min. $R_G = 18\Omega, V_{CEP} = 500V$
$C_{res}$	Reverse transfer capacitance	—	—	—		
$t_{sc}$	Short circuit withstand time	10	—	—	μs	

(1) Includes tail losses

## Thermal and Mechanical Characteristics

Parameter	Description	Typ	Max	Units
$R_{thJC}$ (IGBT)	Thermal resistance, junction to case, each IGBT	—	0.25	
$R_{thJC}$ (Diode)	Thermal resistance, junction to case, each diode	—	0.38	°C/W
$R_{thCS}$ (Module)	Thermal resistance, case to sink	0.041	0.100	
Wt	Weight of module	150	—	g

Refer to Section D - page D-17 for Package Outline11 -INT-A-PAK, New -Half Bridge